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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "<u>Embedded -</u> <u>Microcontrollers</u>"

Details

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Product Status	Obsolete
Core Processor	RL78
Core Size	16-Bit
Speed	32MHz
Connectivity	CSI, I²C, LINbus, UART/USART
Peripherals	DMA, LVD, POR, PWM, WDT
Number of I/O	22
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	4K x 8
RAM Size	4K x 8
Voltage - Supply (Vcc/Vdd)	1.6V ~ 5.5V
Data Converters	A/D 8x8/10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	32-LQFP
Supplier Device Package	32-LQFP (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/renesas-electronics-america/r5f104bcafp-v0

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

1.2 Ordering Information



Part No. R5F104LEAxxxFB#V0 Packaging specification #30: Tray (LFQFP, LQFP) #U0: Tray (HWQFN, WFLGA, FLGA) #V0: Tray (LFQFP, LQFP, LSSOP) #50: Embossed Tape (LFQFP, LQFP) #W0:Embossed Tape (HWQFN, WFLGA, FLGA) #X0: Embossed Tape (LFQFP, LQFP, LSSOP) Package type: SP: LSSOP, 0.65 mm pitch FP: LQFP, 0.80 mm pitch FA: LQFP, 0.65 mm pitch FB: LFQFP, 0.50 mm pitch NA: HWQFN, 0.50 mm pitch LA: WFLGA, 0.50 mm pitch FLGA, 0.50 mm pitch ROM number (Omitted with blank products) Fields of application: A: Consumer applications, TA = -40 to +85 °C D: Industrial applications, TA = -40 to +85 $^{\circ}$ C G: Industrial applications, TA = -40 to +105 °C ROM capacity: A: 16 KB C: 32 KB D: 48 KB E: 64 KB F: 96 KB G: 128 KB H: 192 KB J: 256 KB K: 384 KB L: 512 KB Pin count: A: 30-pin B: 32-pin C: 36-pin E: 40-pin F: 44-pin G: 48-pin J: 52-pin L: 64-pin M: 80-pin P: 100-pin RL78/G14 Memory type: F: Flash memory Renesas MCU Renesas semiconductor product



RL78/G14

1.3.5 44-pin products

• 44-pin plastic LQFP (10 × 10 mm, 0.8 mm pitch)



Note Mounted on the 96 KB or more code flash memory products.

Caution Connect the REGC pin to Vss pin via a capacitor (0.47 to 1 $\mu\text{F}).$

- Remark 1. For pin identification, see 1.4 Pin Identification.
- **Remark 2.** Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register 0, 1 (PIOR0, 1).



1.3.9 80-pin products

- 80-pin plastic LQFP (14 \times 14 mm, 0.65 mm pitch)
- 80-pin plastic LFQFP (12 \times 12 mm, 0.5 mm pitch)



Note Mounted on the 384 KB or more code flash memory products.

- Caution 1. Make EVsso pin the same potential as Vss pin.
- Caution 2. Make VDD pin the potential that is higher than EVDD0 pin.
- Caution 3. Connect the REGC pin to Vss pin via a capacitor (0.47 to 1 μ F).
- Remark 1. For pin identification, see 1.4 Pin Identification.
- **Remark 2.** When using the microcontroller for an application where the noise generated inside the microcontroller must be reduced, it is recommended to supply separate powers to the VDD and EVDD0 pins and connect the Vss and EVss0 pins to separate ground lines.
- **Remark 3.** Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register 0, 1 (PIOR0, 1).

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1.5 Block Diagram

1.5.1 30-pin products



Note Mounted on the 96 KB or more code flash memory products.



[48-pin, 64-pin products (code flash memory 384 KB to 512 KB)]

Caution This outline describes the functions at the time when Peripheral I/O redirection register 0, 1 (PIOR0, 1) are set to 00H.

			(1/2)				
		48-pin	64-pin				
li	tem	R5F104Gx	R5F104Lx				
		(x = K, L)	(x = K, L)				
Code flash memory ((KB)	384 to 512	384 to 512				
Data flash memory (I	KB)	8	8				
RAM (KB)		32 to 48 ^{Note} 32 to 48 ^{Note}					
Address space		1 MB					
Main system clock	High-speed system	X1 (crystal/ceramic) oscillation, external m	ain system clock input (EXCLK)				
	clock	HS (high-speed main) mode: 1 to 20 MHz	: (VDD = 2.7 to 5.5 V),				
		HS (high-speed main) mode: 1 to 16 MHz (VDD = 2.4 to 5.5 V),					
		LS (low-speed main) mode: 1 to 8 MHz	$(V_{DD} = 1.8 \text{ to } 5.5 \text{ V}),$				
		LV (low-voltage main) mode: 1 to 4 MHz	(VDD = 1.6 to 5.5 V)				
	High-speed on-chip	HS (high-speed main) mode: 1 to 32 MHz	: (VDD = 2.7 to 5.5 V),				
	oscillator clock (fiH)	HS (high-speed main) mode: 1 to 16 MHz	: (VDD = 2.4 to 5.5 V),				
		LS (low-speed main) mode: 1 to 8 MHz	(VDD = 1.8 to 5.5 V),				
		LV (low-voltage main) mode: 1 to 4 MHz (VDD = 1.6 to 5.5 V)					
Subsystem clock		XT1 (crystal) oscillation, external subsyste	m clock input (EXCLKS) 32.768 kHz				
Low-speed on-chip oscillator clock		15 kHz (TYP.): VDD = 1.6 to 5.5 V					
General-purpose register		8 bits \times 32 registers (8 bits \times 8 registers \times 4	banks)				
Minimum instruction	execution time	$0.03125\ \mu\text{s}$ (High-speed on-chip oscillator	clock: fiн = 32 MHz operation)				
		0.05 μ s (High-speed system clock: fMX = 2	0 MHz operation)				
		30.5 μ s (Subsystem clock: fsub = 32.768 k	Hz operation)				
Instruction set		Data transfer (8/16 bits)					
		Adder and subtractor/logical operation (8/16 bits)					
		Multiplication (8 bits × 8 bits, 16 bits × 16 bits), Division (16 bits ÷ 16 bits, 32 bits ÷ 32					
		bits)					
		• Multiplication and Accumulation (16 bits × 16 bits + 32 bits)					
		etc.					
I/O port	Total	44	58				
	CMOS I/O	34	48				
	CMOS input	5	5				
	CMOS output	1	1				
	N-ch open-drain I/O	4	4				
	(6 V tolerance)						
Timer	16-bit timer	8 channels					
		(TAU: 4 channels, Timer RJ: 1 channel, Tir	mer RD: 2 channels, Timer RG: 1 channel)				
	Watchdog timer	1 channel					
	Real-time clock	1 channel					
	(RTC)						
	12-bit interval timer	1 channel					
	Timer output	Timer outputs: 14 channels					
		PWM outputs: 9 channels					
	RTC output	1					
		• 1 Hz (subsystem clock: fs∪в = 32.768 kHz)					

(Note is listed on the next page.)



- Note 1. Total current flowing into VDD and EVDD0, including the input leakage current flowing when the level of the input pin is fixed to VDD, EVDD0 or Vss, EVss0. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the A/D converter, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors and the current flowing during data flash rewrite.
- Note 2. When high-speed on-chip oscillator and subsystem clock are stopped.
- Note 3. When high-speed system clock and subsystem clock are stopped.
- Note 4. When high-speed on-chip oscillator and high-speed system clock are stopped. When AMPHS1 = 1 (Ultra-low power consumption oscillation). However, not including the current flowing into the RTC, 12-bit interval timer, and watchdog timer
- Note 5. Relationship between operation voltage width, operation frequency of CPU and operation mode is as below.

HS (high-speed main) mode:	2.7 V \leq VDD \leq 5.5 V@1 MHz to 32 MHz
	2.4 V \leq VDD \leq 5.5 V@1 MHz to 16 MHz
LS (low-speed main) mode:	1.8 V \leq VDD \leq 5.5 V@1 MHz to 8 MHz
LV (low-voltage main) mode:	1.6 V \leq VDD \leq 5.5 V@1 MHz to 4 MHz

- Remark 1. fmx: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
- Remark 2. fHOCO: High-speed on-chip oscillator clock frequency (64 MHz max.) Remark 3. file:
- High-speed on-chip oscillator clock frequency (32 MHz max.) Remark 4. fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
- Remark 5. Except subsystem clock operation, temperature condition of the TYP. value is TA = 25°C

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(3) Flash ROM: 384 to 512 KB of 48- to 100-pin products

(TA = -40 to +85°C, 1.6 V \leq EVDD0 = EVDD1 \leq VDD \leq 5.5 V, VSS = EVSS0 = EVSS1 = 0 V)

Parameter	Symbol		Conditions					TYP.	MAX.	Unit
Supply	IDD1	Operat-	HS (high-speed main)	fносо = 64 MHz,	Basic	VDD = 5.0 V		2.9		mA
current		ing mode	mode Note 5	fiн = 32 MHz Note 3	operation	VDD = 3.0 V		2.9		
NOLE 1				fносо = 32 MHz,	Basic	VDD = 5.0 V		2.5		
				fiн = 32 MHz Note 3	operation	VDD = 3.0 V		2.5		
			HS (high-speed main)	fносо = 64 MHz,	Normal	VDD = 5.0 V		6.0	11.2	mA
			mode Note 5	fiH = 32 MHz Note 3	operation	VDD = 3.0 V		6.0	11.2	
				fносо = 32 MHz,	Normal	VDD = 5.0 V		5.5	10.6	
				fiн = 32 MHz Note 3	operation	VDD = 3.0 V		5.5	10.6	
				fносо = 48 MHz,	Normal	VDD = 5.0 V		4.7	8.6	
				fiн = 24 MHz Note 3	operation	VDD = 3.0 V		4.7	8.6	
				fносо = 24 MHz,	Normal	VDD = 5.0 V		4.4	8.2	
				fin = 24 MHz Note 3	operation	VDD = 3.0 V		4.4	8.2	
				fносо = 16 MHz,	Normal	VDD = 5.0 V		3.3	5.9	
		fiн = 16 MHz ^{Note 3}	operation	VDD = 3.0 V		3.3	5.9			
	LS (low-speed main)	fносо = 8 MHz,	Normal	VDD = 3.0 V		1.5	2.5	mA		
			mode Note 5	fin = 8 MHz Note 3	operation	VDD = 2.0 V		1.5	2.5	
			LV (low-voltage main)	fносо = 4 MHz,	Normal	VDD = 3.0 V		1.5	2.1	mA
			mode Note 5	fin = 4 MHz Note 3	operation	VDD = 2.0 V		1.5	2.1	
		HS (high-speed main)	f _{MX} = 20 MHz ^{Note 2} ,	Normal	Square wave input		3.7	6.8	mA	
		mode Note 5	VDD = 5.0 V	operation	Resonator connection		3.9	7.0		
				f _{MX} = 20 MHz ^{Note 2} , V _{DD} = 3.0 V	Normal	Square wave input		3.7	6.8	-
			1		operation	Resonator connection		3.9	7.0	
				f _{MX} = 10 MHz ^{Note 2} , V _{DD} = 5.0 V	Normal operation	Square wave input		2.3	4.1	
						Resonator connection		2.3	4.2	
				f _{MX} = 10 MHz ^{Note 2} ,	Normal	Square wave input		2.3	4.1	
				VDD = 3.0 V	operation	Resonator connection		2.3	4.2	
			LS (low-speed main)	f _{MX} = 8 MHz ^{Note 2} ,	Normal	Square wave input		1.4	2.4	mA
			mode Note 5	VDD = 3.0 V	operation	Resonator connection		1.4	2.5	
				f _{MX} = 8 MHz ^{Note 2} ,	Normal	Square wave input		1.4	2.4	
				V _{DD} = 2.0 V	operation	Resonator connection		1.4	2.5	
			Subsystem clock	fsue = 32.768 kHz Note 4	Normal	Square wave input		5.2		μΑ
			operation	TA = -40°C	operation	Resonator connection		5.2		
				fsub = 32.768 kHz Note 4	Normal	Square wave input		5.3	7.7	
				TA = +25°C	operation	Resonator connection		5.3	7.7	
				fsue = 32.768 kHz Note 4	Normal	Square wave input		5.5	10.6	
				T _A = +50°C	operation	Resonator connection		5.5	10.6	
				fsue = 32.768 kHz Note 4	Normal	Square wave input		5.9	13.2	
				TA = +70°C	operation	Resonator connection		6.0	13.2	
				fsub = 32.768 kHz ^{Note 4}	Normal	Square wave input		6.8	17.5	
				TA = +85°C	operation	Resonator connection		6.9	17.5	

(Notes and Remarks are listed on the next page.)



(4) Peripheral Functions (Common to all products)

(TA = -40 to +85°C, 1.6 V \leq EVDD0 = EVDD1 \leq VDD \leq 5.5 V, Vss = EVss0 = EVss1 = 0 V)

Parameter	Symbol	Conditions			TYP.	MAX.	Unit
Low-speed on-chip oscilla- tor operating current	I _{FIL} Note 1				0.20		μA
RTC operating current	IRTC Notes 1, 2, 3				0.02		μΑ
12-bit interval timer operat- ing current	I _{IT} Notes 1, 2, 4				0.02		μA
Watchdog timer operating current	IWDT Notes 1, 2, 5	fi∟ = 15 kHz			0.22		μA
A/D converter operating cur- rent	IADC Notes 1, 6	When conversion at maximum Normal mode, speed AVREFP = VDD = 5.0 V			1.3	1.7	mA
			Low voltage mode, AV _{REFP} = V _{DD} = 3.0 V		0.5	0.7	mA
A/D converter reference voltage current	IADREF Note 1				75.0		μA
Temperature sensor operat- ing current	ITMPS Note 1				75.0		μA
D/A converter operating cur- rent	IDAC Notes 1, 11, 13	Per D/A converter channel			1.5	mA	
Comparator operating cur-	I _{CMP} Notes 1, 12, 13 V _{DD} = 5.0 V, Regulator output voltage = 2.1 V	VDD = 5.0 V,	Window mode		12.5		μA
rent		Comparator high-speed mode		6.5		μΑ	
			Comparator low-speed mode		1.7		μA
		VDD = 5.0 V,	Window mode		8.0		μA
		Regulator output voltage = 1.8 V	Comparator high-speed mode		4.0		μΑ
			Comparator low-speed mode		1.3		μΑ
LVD operating current	ILVD Notes 1, 7				0.08		μΑ
Self-programming operat- ing current	IFSP Notes 1, 9				2.50	12.20	mA
BGO operating current	IBGO Notes 1, 8				2.50	12.20	mA
SNOOZE operating current	ISNOZ Note 1	ADC operation	The mode is performed Note 10		0.50	0.60	mA
			The A/D conversion opera- tions are performed, Low volt- age mode, AV _{REFP} = V _{DD} = 3.0 V		1.20	1.44	
		CSI/UART operation	-		0.70	0.84	
		DTC operation			3.10		

Note 1. Current flowing to VDD.

Note 2. When high speed on-chip oscillator and high-speed system clock are stopped.

Note 3. Current flowing only to the real-time clock (RTC) (excluding the operating current of the low-speed on-chip oscillator and the XT1 oscillator). The supply current of the RL78 microcontrollers is the sum of the values of either IDD1 or IDD2, and IRTC, when the real-time clock operates in operation mode or HALT mode. When the low-speed on-chip oscillator is selected, IFIL should be added. IDD2 subsystem clock operation includes the operational current of the real-time clock.

Note 4. Current flowing only to the 12-bit interval timer (excluding the operating current of the low-speed on-chip oscillator and the XT1 oscillator). The supply current of the RL78 microcontrollers is the sum of the values of either IDD1 or IDD2, and IIT, when the 12-bit interval timer operates in operation mode or HALT mode. When the low-speed on-chip oscillator is selected, IFIL should be added.



CSI mode serial transfer timing (master mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)





- Remark 1. p: CSI number (p = 00, 01, 10, 20, 30, 31), m: Unit number (m = 0, 1), n: Channel number (n = 0 to 3), g: PIM and POM number (g = 0, 1, 3 to 5, 14)
- Remark 2. CSI01 of 48-, 52-, 64-pin products, and CSI11 and CSI21 cannot communicate at different potential. Use other CSI for communication at different potential.

RL78/G14

(9) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (slave mode, SCKp... external clock input)

Parameter	Symbol	Cor	Conditions		HS (high-speed main) mode		LS (low-speed main) mode		LV (low-voltage main) mode	
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	tксү2	$4.0~V \leq EV_{DD0} \leq 5.5~V,$	24 MHz < fмск	14/fмск		_		_		ns
Note 1		$2.7~V \leq V_b \leq 4.0~V$	$20 \text{ MHz} < f_{MCK} \leq 24 \text{ MHz}$	12/fмск		—				ns
			$8 \text{ MHz} < \text{fmck} \le 20 \text{ MHz}$	10/fмск		_				ns
			$4 \text{ MHz} < f_{MCK} \le 8 \text{ MHz}$	8/fмск		16/fмск		_		ns
			fмск ≤ 4 MHz	6/fмск		10/fмск		10/fмск		ns
		$2.7~V \leq EV_{DD0} < 4.0~V,$	24 MHz < fмск	20/fмск		—		_		ns
		$2.3 \text{ V} \leq \text{V}_b \leq 2.7 \text{ V}$	20 MHz < fмск ≤ 24 MHz	16/fмск		—		_		ns
			16 MHz < fмск ≤ 20 MHz	14/fмск		—		_		ns
			$8 \text{ MHz} < \text{fmck} \le 16 \text{ MHz}$	12/fмск		_		_		ns
			$4 \text{ MHz} < \text{fmck} \le 8 \text{ MHz}$	8/fмск		16/fмск		_		ns
	1.8 V ≤ EVDD		fмск ≤ 4 MHz	6/fмск		10/fмск		10/fмск		ns
		$1.8 \text{ V} \leq \text{EV}_{\text{DD0}} < 3.3 \text{ V},$	24 MHz < fмск	48/fмск		_		_		ns
		1.6 V ≤ Vb ≤ 2.0 V Note 2	20 MHz < fмск ≤ 24 MHz	36/fмск		_		_		ns
		1002	16 MHz < fmck \leq 20 MHz	32/fмск		—		_		ns
		$8 \text{ MHz} < \text{fmck} \le 16 \text{ MHz}$	26/fмск		_		_		ns	
		$4 \text{ MHz} < \text{fmck} \le 8 \text{ MHz}$	16/fмск		16/fмск		_		ns	
			fмск ≤ 4 MHz	10/fмск		10/fмск		10/fмск		ns
SCKp high-/ low-level width	tкн2, tкL2	$4.0 \text{ V} \le \text{EV}_{\text{DD0}} \le 5.5 \text{ V}, 2$	$2.7 \text{ V} \leq V_b \leq 4.0 \text{ V}$	tксү2/2 - 12		tксү2/2 - 50		tксү2/2 - 50		ns
		$2.7 \text{ V} \le \text{EV}_{\text{DD0}} < 4.0 \text{ V}, 2$	$2.3 \text{ V} \leq V_b \leq 2.7 \text{ V}$	tксү2/2 - 18		tксү2/2 - 50		tксү2/2 - 50		ns
		$1.8 \text{ V} \le \text{EV}_{\text{DD0}} < 3.3 \text{ V}, ^{2}$	$1.6 \text{ V} \leq V_b \leq 2.0 \text{ V} \text{ Note } 2$	tксү2/2 - 50		tксү2/2 - 50		tксү2/2 - 50		ns
SIp setup time (to SCKp↑) ^{Note 3}	tsık2	$4.0 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 5.5 \text{ V}, 2$	$2.7 \text{ V} \leq V_b \leq 4.0 \text{ V}$	1/fмск + 20		1/fмск + 30		1/fмск + 30		ns
		$2.7 \text{ V} \le \text{EV}_{\text{DD0}} < 4.0 \text{ V}, 2$	1/fмск + 20		1/fмск + 30		1/fмск + 30		ns	
		$1.8 \text{ V} \le \text{EV}_{\text{DD0}} < 3.3 \text{ V}, ^{2}$	$1.6 \text{ V} \leq V_b \leq 2.0 \text{ V} \text{ Note 2}$	1/fмск + 30		1/fмск + 30		1/fмск + 30		ns
SIp hold time (from SCKp↑) Note 4	tksi2			1/fмск + 31		1/fмск + 31		1/fмск + 31		ns
Delay time from SCKp↓ to SOp	tkso2	4.0 V \leq EVDD0 \leq 5.5 V, 2 Cb = 30 pF, Rb = 1.4 kΩ	$2.7 \text{ V} \leq \text{Vb} \leq 4.0 \text{ V},$		2/fмск + 120		2/fмск + 573		2/fмск + 573	ns
output ^{Note 5}		$\begin{array}{l} 2.7 \ V \leq EV_{DD0} < 4.0 \ V, 2 \\ C_b = 30 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$	$2.3 \text{ V} \le \text{V}_{\text{b}} \le 2.7 \text{ V},$		2/fмск + 214		2/fмск + 573		2/fмск + 573	ns
		$\begin{array}{l} 1.8 \ V \leq EV_{DD0} < 3.3 \ V, \\ C_b = 30 \ pF, \ R_V = 5.5 \ k\Omega \end{array}$	$1.6 \text{ V} \le \text{V}_b \le 2.0 \text{ V} \text{ Note 2},$		2/fмск + 573		2/fмск + 573		2/fмск + 573	ns

($(T_A = -40 \text{ to } +85^{\circ}\text{C})$	18V<	< Vnn < 5 5 V	Vss = EVsso	= FVSS1 = 0	٧١
	1 = -40 10 + 00 0	1.0 V -		, v 33 – L v 330		• /

(Notes, Caution, and Remarks are listed on the next page.)



- Note 1. Transfer rate in the SNOOZE mode: MAX. 1 Mbps
- Note 2. Use it with $EVDD0 \ge Vb$.
- Note 3. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- Note 4. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The Slp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- Note 5. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- Caution Select the TTL input buffer for the SIp pin and SCKp pin, and the N-ch open drain output (VoD tolerance (for the 30- to 52-pin products)/EVoD tolerance (for the 64- to 100-pin products)) mode for the SOp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

CSI mode connection diagram (during communication at different potential)



- **Remark 1.** Rb[Ω]: Communication line (SOp) pull-up resistance, Cb[F]: Communication line (SOp) load capacitance, Vb[V]: Communication line voltage
- **Remark 2.** p: CSI number (p = 00, 01, 10, 20, 30, 31), m: Unit number (m = 0, 1), n: Channel number (n = 0 to 3), g: PIM and POM number (g = 0, 1, 3 to 5, 14)
- Remark 3. fMCK: Serial array unit operation clock frequency (Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00, 01, 02, 10, 12, 13))
- Remark 4. CSI01 of 48-, 52-, 64-pin products, and CSI11 and CSI21 cannot communicate at different potential. Use other CSI for communication at different potential.
 Also, communication at different potential cannot be performed during clock synchronous serial communication with the slave select function.



Simplified I²C mode connection diagram (during communication at different potential)



Simplified I²C mode serial transfer timing (during communication at different potential)



- **Remark 1.** Rb[Ω]: Communication line (SDAr, SCLr) pull-up resistance, Cb[F]: Communication line (SDAr, SCLr) load capacitance, Vb[V]: Communication line voltage
- Remark 2. r: IIC number (r = 00, 01, 10, 11, 20, 30, 31), g: PIM, POM number (g = 0, 1, 3 to 5, 14)
- Remark 3. fMCK: Serial array unit operation clock frequency
 - (Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number (m = 0, 1), n: Channel number (n = 0, 2), mn = 00, 01, 02, 10, 12, 13)



(2) When reference voltage (+) = AVREFP/ANIO (ADREFP1 = 0, ADREFP0 = 1), reference voltage (-) = AVREFM/ANI1 (ADREFM = 1), target pin: ANI16 to ANI20

 $(TA = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{EVDD0} = \text{EVDD1} \le \text{VDD} \le 5.5 \text{ V}, 1.6 \text{ V} \le \text{AVREFP} \le \text{VDD} \le 5.5 \text{ V}, \text{Vss} = \text{EVss0} = \text{EVss1} = 0 \text{ V}, \text{Reference voltage (+)} = \text{AVREFP}, \text{Reference voltage (-)} = \text{AVREFM} = 0 \text{ V})$

Parameter	Symbol	Condi	itions	MIN.	TYP.	MAX.	Unit
Resolution	RES			8		10	bit
Overall error Note 1	AINL	10-bit resolution	$1.8~V \leq AV_{\text{REFP}} \leq 5.5~V$		1.2	±5.0	LSB
		$EV_{DD0} \le AV_{REFP} = V_{DD}$ Notes 3, 4	$1.6 \text{ V} \le \text{AV}_{\text{REFP}} \le 5.5 \text{ V}^{\text{Note 5}}$		1.2	±8.5	LSB
Conversion time	tconv	10-bit resolution	$3.6~V \leq V_{DD} \leq 5.5~V$	2.125		39	μs
		Target ANI pin: ANI16 to ANI20	$2.7~V \leq V_{DD} \leq 5.5~V$	3.1875		39	μs
			$1.8~V \le V_{DD} \le 5.5~V$	17		39	μs
			$1.6~V \leq V_{DD} \leq 5.5~V$	57		95	μs
Zero-scale error Notes 1, 2	Ezs	10-bit resolution	$1.8 \text{ V} \leq \text{AV}_{\text{REFP}} \leq 5.5 \text{ V}$			±0.35	%FSR
		$EV_{DD0} \le AV_{REFP} = V_{DD}$ Notes 3, 4	$1.6 \text{ V} \le \text{AV}_{\text{REFP}} \le 5.5 \text{ V}^{\text{Note 5}}$			±0.60	%FSR
Full-scale error Notes 1, 2	Efs	10-bit resolution $EV_{DD0} \le AV_{REFP} = V_{DD}$ Notes 3, 4	$1.8 \text{ V} \leq \text{AV}_{\text{REFP}} \leq 5.5 \text{ V}$			±0.35	%FSR
			$1.6 \text{ V} \le \text{AV}_{\text{REFP}} \le 5.5 \text{ V}^{\text{Note 5}}$			±0.60	%FSR
Integral linearity error Note 1	ILE	10-bit resolution	$1.8 \text{ V} \leq \text{AV}_{\text{REFP}} \leq 5.5 \text{ V}$			±3.5	LSB
		$EV_{DD0} \leq AV_{REFP} = V_{DD}$ Notes 3, 4	$1.6~V \leq AV_{REFP} \leq 5.5~V$ Note 5			±6.0	LSB
Differential linearity error Note 1	DLE	10-bit resolution	$1.8 \text{ V} \leq \text{AV}_{\text{REFP}} \leq 5.5 \text{ V}$			±2.0	LSB
		$EV_{DD0} \le AV_{REFP} = V_{DD}$ Notes 3, 4	$1.6 \text{ V} \le \text{AV}_{\text{REFP}} \le 5.5 \text{ V}^{\text{Note 5}}$			±2.5	LSB
Analog input voltage	VAIN	ANI16 to ANI20		0		AVREFP and EVDD0	V

Note 1. Excludes quantization error (±1/2 LSB).

Note 2. This value is indicated as a ratio (%FSR) to the full-scale value.

Note 3. When $EVDD0 \le AVREFP \le VDD$, the MAX. values are as follows.

 Overall error:
 Add ±1.0 LSB to the MAX. value when AVREFP = VDD.

 Zero-scale error/Full-scale error:
 Add ±0.05%FSR to the MAX. value when AVREFP = VDD.

 Integral linearity error/ Differential linearity error:
 Add ±0.5 LSB to the MAX. value when AVREFP = VDD.

 Note 4.
 When AVREFP < EVDD0 ≤ VDD, the MAX. values are as follows.</td>

 Overall error:
 Add ±4.0 LSB to the MAX. value when AVREFP = VDD.

 Zero-scale error/Full-scale error:
 Add ±0.20%FSR to the MAX. value when AVREFP = VDD.

Integral linearity error/ Differential linearity error: Add ±2.0 LSB to the MAX. value when AVREFP = VDD.

Note 5. When the conversion time is set to 57 μ s (min.) and 95 μ s (max.).



(3) When reference voltage (+) = VDD (ADREFP1 = 0, ADREFP0 = 0), reference voltage (-) = Vss (ADREFM = 0), target pin: ANI0 to ANI14, ANI16 to ANI20, internal reference voltage, and temperature sensor output voltage

(TA = -40 to +85°C, 1.6 V \leq EVDD0 = EVDD1 \leq VDD \leq 5.5 V, Vss = EVss0 = EVss1 = 0 V, Reference voltage (+) = VDD, Reference voltage (-) = Vss)

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Resolution	RES			8		10	bit
Overall error Note 1	AINL	10-bit resolution	$1.8 \text{ V} \leq \text{V}\text{DD} \leq 5.5 \text{ V}$		1.2	±7.0	LSB
			$1.6 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}^{\text{Note 3}}$		1.2	±10.5	LSB
Conversion time	tconv	10-bit resolution	$3.6~V \le V_{DD} \le 5.5~V$	2.125		39	μs
		larget pin: ANI0 to ANI14, ANI16 to ANI20	$2.7~V \leq V_{DD} \leq 5.5~V$	3.1875		39	μs
			$1.8~V \le V_{DD} \le 5.5~V$	17		39	μs
			$1.6~V \leq V_{DD} \leq 5.5~V$	57		95	μs
		10-bit resolution	$3.6~V \le V_{DD} \le 5.5~V$	2.375		39	μs
		larget pin: internal reference voltage, and temperature sensor output voltage (HS (high-speed main) mode)	$2.7~V \leq V_{DD} \leq 5.5~V$	3.5625		39	μs
			$2.4~V \leq V \text{DD} \leq 5.5~V$	17		39	μs
Zero-scale error Notes 1, 2	Ezs	10-bit resolution	$1.8~V \le V_{DD} \le 5.5~V$			±0.60	%FSR
			1.6 V \leq VDD \leq 5.5 V Note 3			±0.85	%FSR
Full-scale error Notes 1, 2	Efs	10-bit resolution	$1.8~V \leq V_{DD} \leq 5.5~V$			±0.60	%FSR
			$1.6~V \leq V_{DD} \leq 5.5~V$ Note 3			±0.85	%FSR
Integral linearity error Note 1	ILE	10-bit resolution	$1.8~V \le V_{DD} \le 5.5~V$			±4.0	LSB
			$1.6~V \leq V_{DD} \leq 5.5~V$ Note 3			±6.5	LSB
Differential linearity error	DLE	10-bit resolution	$1.8~V \le V_{DD} \le 5.5~V$			±2.0	LSB
Note 1			$1.6~V \leq V_{DD} \leq 5.5~V$ Note 3			±2.5	LSB
Analog input voltage	Vain	ANI0 to ANI14		0		Vdd	V
		ANI16 to ANI20				EV _{DD0}	V
	Internal reference voltage (2.4 V \leq V _{DD} \leq 5.5 V, HS (high-speed main) mode)			\ \	/ _{BGR} Note	4	V
Temperature sensor output voltage $(2.4 V \le V_{DD} \le 5.5 V, HS (high-speed main) mode)$				VTMPS25 Note 4			V

Note 1. Excludes quantization error (±1/2 LSB).

Note 2. This value is indicated as a ratio (% FSR) to the full-scale value.

Note 3. When the conversion time is set to 57 μ s (min.) and 95 μ s (max.).

Note 4. Refer to 2.6.2 Temperature sensor characteristics/internal reference voltage characteristic.



Operation of products rated "G: Industrial applications (TA = -40 to + $105^{\circ}C$)" at ambient operating temperatures above $85^{\circ}C$ differs from that of products rated "A: Consumer applications" and "D: Industrial applications" in the ways listed below.

Parameter	A: Consumer applications, D: Industrial applications	G: Industrial applications
Operating ambient temperature	TA = -40 to +85°C	TA = -40 to +105°C
Operating mode	HS (high-speed main) mode:	HS (high-speed main) mode only:
Operating voltage range	$2.7 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}_{@}1 \text{ MHz to } 32 \text{ MHz}$	$2.7 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}_{@}1 \text{ MHz}$ to 32 MHz
	2.4 V \leq VDD \leq 5.5 V@1 MHz to 16 MHz	2.4 V \leq VDD \leq 5.5 V@1 MHz to 16 MHz
	LS (low-speed main) mode:	
	1.8 V \leq VDD \leq 5.5 V@1 MHz to 8 MHz	
	LV (low-voltage main) mode:	
	1.6 V \leq VDD \leq 5.5 V@1 MHz to 4 MHz	
High-speed on-chip oscillator	$1.8 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}$:	$2.4 \text{ V} \leq \text{V}_{DD} \leq 5.5 \text{ V}$:
clock accuracy	±1.0% @ TA = -20 to +85°C	±2.0% @ TA = +85 to +105°C
	±1.5% @ TA = -40 to -20°C	±1.0% @ TA = -20 to +85°C
	$1.6 \text{ V} \le \text{V}_{\text{DD}} < 1.8 \text{ V}$:	±1.5% @ TA = -40 to -20°C
	±5.0% @ TA = -20 to +85°C	
	±5.5% @ TA = -40 to -20°C	
Serial array unit	UART	UART
	CSI: fcLk/2 (16 Mbps supported), fcLk/4	CSI: fclk/4
	Simplified I ² C communication	Simplified I ² C communication
IICA	Standard mode	Standard mode
	Fast mode	Fast mode
	Fast mode plus	
Voltage detector	• Rising: 1.67 V to 4.06 V (14 stages)	• Rising: 2.61 V to 4.06 V (8 stages)
	Falling: 1.63 V to 3.98 V (14 stages)	Falling: 2.55 V to 3.98 V (8 stages)

Remark The electrical characteristics of products rated "G: Industrial applications (TA = -40 to + 105°C)" at ambient operating temperatures above 85°C differ from those of products rated "A: Consumer applications" and "D: Industrial applications". For details, refer to **3.1** to **3.10**.



3.2 Oscillator Characteristics

3.2.1 X1, XT1 characteristics

$(TA = -40 \text{ to } +105^{\circ}C, 2.4 \text{ V} \le \text{VDD} \le 5.5 \text{ V}, \text{Vss} = 0 \text{ V})$

Resonator	Resonator	Conditions	MIN.	TYP.	MAX.	Unit
X1 clock oscillation frequency (fx) Note	Ceramic resonator/	$2.7~V \leq V \text{DD} \leq 5.5~V$	1.0		20.0	MHz
	crystal resonator	$2.4 \text{ V} \leq \text{V}_{\text{DD}} \leq 2.7 \text{ V}$	1.0		16.0	
XT1 clock oscillation frequency (fxT) Note	Crystal resonator		32	32.768	35	kHz

Note Indicates only permissible oscillator frequency ranges. Refer to AC Characteristics for instruction execution time. Request evaluation by the manufacturer of the oscillator circuit mounted on a board to check the oscillator characteristics.

Caution Since the CPU is started by the high-speed on-chip oscillator clock after a reset release, check the X1 clock oscillation stabilization time using the oscillation stabilization time counter status register (OSTC) by the user. Determine the oscillation stabilization time of the OSTC register and the oscillation stabilization time select register (OSTS) after sufficiently evaluating the oscillation stabilization time with the resonator to be used.

Remark When using the X1 oscillator and XT1 oscillator, refer to 5.4 System Clock Oscillator in the RL78/G14 User's Manual.

3.2.2 On-chip oscillator characteristics

(TA = -40 to +105°C, 2.4 V \leq VDD \leq 5.5 V, Vss = 0 V)

Oscillators	Parameters	Conditions		MIN.	TYP.	MAX.	Unit
High-speed on-chip oscillator clock frequency Notes 1, 2	fін			1		32	MHz
High-speed on-chip oscillator clock frequency		-20 to +85°C	$2.4~V \leq V \text{DD} \leq 5.5~V$	-1.0		+1.0	%
accuracy		-40 to -20°C	$2.4~V \leq V \text{DD} \leq 5.5~V$	-1.5		+1.5	%
		+85 to +105°C	$2.4~V \leq V \text{DD} \leq 5.5~V$	-2.0		+2.0	%
Low-speed on-chip oscillator clock frequency	fı∟				15		kHz
Low-speed on-chip oscillator clock frequency accuracy				-15		+15	%

Note 1. High-speed on-chip oscillator frequency is selected with bits 0 to 4 of the option byte (000C2H) and bits 0 to 2 of the HOCODIV register.

Note 2. This only indicates the oscillator characteristics. Refer to AC Characteristics for instruction execution time.



3.6 Analog Characteristics

3.6.1 A/D converter characteristics

Classification of A/D converter characteristics

Reference Voltage Input channel	Reference voltage (+) = AVREFP Reference voltage (-) = AVREFM	Reference voltage (+) = V _{DD} Reference voltage (-) = V _{SS}	Reference voltage (+) = V _{BGR} Reference voltage (-)= AV _{REFM}		
ANI0 to ANI14	Refer to 3.6.1 (1).	Refer to 3.6.1 (3).	Refer to 3.6.1 (4).		
ANI16 to ANI20	Refer to 3.6.1 (2).				
Internal reference voltage Temperature sensor output voltage	Refer to 3.6.1 (1) .		_		

(1) When reference voltage (+) = AVREFP/ANI0 (ADREFP1 = 0, ADREFP0 = 1), reference voltage (-) = AVREFM/ANI1 (ADREFM = 1), target pin: ANI2 to ANI14, internal reference voltage, and temperature sensor output voltage

(TA = -40 to +105°C, 2.4 V \leq AVREFP \leq VDD \leq 5.5 V, Vss = 0 V, Reference voltage (+) = AVREFP, Reference voltage (-) = AVREFM = 0 V)

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Resolution	RES			8		10	bit
Overall error Note 1	AINL	10-bit resolution AV _{REFP} = V _{DD} Note 3	$2.4 \text{ V} \leq \text{AV}_{\text{REFP}} \leq 5.5 \text{ V}$		1.2	±3.5	LSB
Conversion time	tconv	10-bit resolution Target pin: ANI2 to ANI14	$3.6~V \leq V_{DD} \leq 5.5~V$	2.125		39	μs
			$2.7~V \leq V_{DD} \leq 5.5~V$	3.1875		39	μs
			$2.4~V \leq V_{DD} \leq 5.5~V$	17		39	μs
		10-bit resolution Target pin: Internal reference voltage, and temperature sensor output volt- age (HS (high-speed main) mode)	$3.6~V \leq V_{DD} \leq 5.5~V$	2.375		39	μs
			$2.7~V \leq V_{DD} \leq 5.5~V$	3.5625		39	μs
			$2.4~\text{V} \leq \text{V}_{\text{DD}} \leq 5.5~\text{V}$	17		39	μs
Zero-scale error Notes 1, 2	Ezs	10-bit resolution AV _{REFP} = V _{DD} Note 3	$2.4 \text{ V} \leq \text{AV}_{\text{REFP}} \leq 5.5 \text{ V}$			±0.25	%FSR
Full-scale error Notes 1, 2	Efs	10-bit resolution AV _{REFP} = V _{DD} Note 3	$2.4 \text{ V} \leq \text{AV}_{\text{REFP}} \leq 5.5 \text{ V}$			±0.25	%FSR
Integral linearity error Note 1	ILE	10-bit resolution AV _{REFP} = V _{DD} Note 3	$2.4 \text{ V} \le \text{AV}_{\text{REFP}} \le 5.5 \text{ V}$			±2.5	LSB
Differential linearity error Note 1	DLE	10-bit resolution AV _{REFP} = V _{DD} Note 3	$2.4 \text{ V} \le \text{AV}_{\text{REFP}} \le 5.5 \text{ V}$			±1.5	LSB
Analog input voltage	Vain	ANI2 to ANI14		0		AVREFP	V
		Internal reference voltage output (2.4 V \leq VDD \leq 5.5 V, HS (high-speed main) mode)		V _{BGR} Note 4			V
		Temperature sensor output voltage (2.4 V \leq V _{DD} \leq 5.5 V, HS (high-speed m	nain) mode)	VT	MPS25 Not	e 4	V

Note 1. Excludes quantization error (±1/2 LSB).

Note 2. This value is indicated as a ratio (%FSR) to the full-scale value.

 Note 3.
 When AVREFP < VDD, the MAX. values are as follows.</td>

 Overall error:
 Add ±1.0 LSB to the MAX. value when AVREFP = VDD.

 Zero-scale error/Full-scale error:
 Add ±0.05%FSR to the MAX. value when AVREFP = VDD.

 Integral linearity error/ Differential linearity error:
 Add ±0.5 LSB to the MAX. value when AVREFP = VDD.

 Note 4.
 Refer to 3.6.2 Temperature sensor characteristics/internal reference voltage characteristic.



3.10 Timing of Entry to Flash Memory Programming Modes

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
How long from when an external reset ends until the initial communication settings are specified	tsuinit	POR and LVD reset must end before the external reset ends.			100	ms
How long from when the TOOL0 pin is placed at the low level until an external reset ends	tsu	POR and LVD reset must end before the external reset ends.	10			μs
How long the TOOL0 pin must be kept at the low level after an external reset ends (excluding the processing time of the firmware to control the flash memory)	thd	POR and LVD reset must end before the external reset ends.	1			ms



<1> The low level is input to the TOOL0 pin.

<2> The external reset ends (POR and LVD reset must end before the external reset ends).

<3> The TOOL0 pin is set to the high level.

<4> Setting of the flash memory programming mode by UART reception and complete the baud rate setting.

- **Remark** tsuinit. The segment shows that it is necessary to finish specifying the initial communication settings within 100 ms from when the external resets end.
 - tsu: How long from when the TOOL0 pin is placed at the low level until a pin reset ends
 - tHD: How long to keep the TOOL0 pin at the low level from when the external resets end
 - (excluding the processing time of the firmware to control the flash memory)



R5F104LCALA, R5F104LDALA, R5F104LEALA, R5F104LFALA, R5F104LGALA, R5F104LHALA, R5F104LJALA R5F104LKALA, R5F104LLALA

R5F104LCGLA,R5F104LDGLA, R5F104LEGLA, R5F104LFGLA, R5F104LGGLA, R5F104LHGLA, R5F104LJGLA R5F104LKGLA, R5F104LLGLA



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RENESAS

REVISION HISTORY

RL78/G14 Datasheet

Boy	Data	Description			
Rev.	Rev. Date –		Summary		
0.01	Feb 10, 2011	—	First Edition issued		
0.02	May 01, 2011	1 to 2	1.1 Features revised		
		3	1.2 Ordering Information revised		
		4 to 13	1.3 Pin Configuration (Top View) revised		
		14	1.4 Pin Identification revised		
		15 to 17	1.5.1 30-pin products to 1.5.3 36-pin products revised		
		23 to 26	1.6 Outline of Functions revised		
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		41 to 97	2. ELECTRICAL SPECIFICATIONS added		
2.00	Oct 25, 2013	1	Modification of 1.1 Features		
		3 to 8	Modification of 1.2 Ordering Information		
		9 to 22	Modification of package type in 1.3 Pin Configuration (Top View)		
		34 to 43	Modification of description of subsystem clock in 1.6 Outline of Functions		
		34 to 43	Modification of description of timer output in 1.6 Outline of Functions		
		34 to 43	Modification of error of data transfer controller in 1.6 Outline of Functions		
		34 to 43	Modification of error of event link controller in 1.6 Outline of Functions		
		45, 46	Modification of description of Tables in 2.1 Absolute Maximum Ratings		
		47	Modification of Tables, notes, cautions, and remarks in 2.2 Oscillator Characteristics		
		48	Modification of error of conditions of high level input voltage in 2.3.1 Pin characteristics		
		49	Modification of error of conditions of low level output voltage in 2.3.1 Pin characteristics		
		53 to 62	Modification of Notes and Remarks in 2.3.2 Supply current characteristics		
		65, 66	Addition of Minimum Instruction Execution Time during Main System Clock Operation		
		67 to 69	Addition of AC Timing Test Points		
		70 to 97	Addition of LS mode and LV mode characteristics in 2.5.1 Serial array unit		
		98 to 101	Addition of LS mode and LV mode characteristics in 2.5.2 Serial interface IICA		
		102 to 105	Addition of characteristics about conversion of internal reference voltage and temperature sensor in 2.6.1 A/D converter characteristics		
		107	Addition of characteristic in 2.6.4 Comparator		
		107	Deletion of detection delay in 2.6.5 POR circuit characteristics		
		109	Modification of 2.6.7 Power supply voltage rising slope characteristics		
		110	Modification of 2.7 Data Memory STOP Mode Low Supply Voltage Data Retention Characteristics		
		110	Addition of characteristic in 2.8 Flash Memory Programming Characteristics		
		111	Addition of description in 2.10 Timing for Switching Flash Memory Programming Modes		